

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10671548	MURAKAWA, AKIRA
	<b>Examiner</b>	<b>Art Unit</b>
	Gee, Jason	2434

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
713	156, 173	5/10/2010	JKG

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST - USPGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	5/10/2010	JKG
PALM - Inventor Name Search	5/10/2010	JKG
Google Scholar - Root Certificates	5/10/2010	JKG

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
713	156, 173	5/10/2010	JKG

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